

TEST REPORT

FCC Part 22 Subpart H

Report	Reference	No:	CTL1702156501-WF04
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Compiled by: Allen Wang (position+printed name+signature) (File administrators)

Tested by:

(position+printed name+signature)

Approved by:

(position+printed name+signature)

Nice Nong (Test Engineer)

> Ivan Xie (Manager)

Allen Wang
Nice Nong

Product Name 8 inch 4G Tablet

Model/Type reference: TT800Q

List Model(s)..... N/A

Trade Mark.....: N/A

FCC ID..... 2AGCDJACS800Q

Applicant's name JACS SOLUTIONS LLC

Address of applicant.....: 8808 Centre Park Drive Suite 305 Columbia, MD 21045, USA

Test Firm..... Shenzhen CTL Testing Technology Co., Ltd.

Floor 1-A, Baisha Technology Park, No.3011, Shahexi Road, Address of Test Firm

Nanshan District, Shenzhen, China 518055

Test specification:

Standard FCC CFR Title 47 Part 2, Part 22H

EIA/TIA 603-D: 2010 KDB 971168 D01

TRF Originator...... Shenzhen CTL Testing Technology Co., Ltd.

Master TRF.....: Dated 2011-01

Date of Receipt...... Jun. 15, 2017

Date of Test Date Jun. 16, 2017–Jul. 11, 2017

Data of Issue...... Jul. 12, 2017

Result..... Pass

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TEST REPORT

Toot Donort No.	CTL1702156501-WF04	Jul. 12, 2017
Test Report No. :	C1L1702150501-WF04	Date of issue

Equipment under Test : 8 inch 4G Tablet

Model /Type : TT800Q

Listed Models : N/A

Applicant : JACS SOLUTIONS LLC

Address : 8808 Centre Park Drive Suite 305 Columbia, MD

21045, USA

Manufacturer : SHENZHEN JIZHAO INFORMATION

TECHNOLOGY CO., LTD.

Address : BUILDING NO.1 ZHONGKENUO INDUSTRIAL

PARK HEZHOU ROAD XIXIANG STREET BAOAN

Report No.: CTL1702156501-WF04

DISTRICT SHENZHEN, CHINA

Test result	Pass *

^{*}In the configuration tested, the EUT complied with the standards specified page 5.

The test report merely corresponds to the test sample.

It is not permitted to copy extracts of these test result without the written permission of the test laboratory.

** Modified History **

Revisions	Description	Issued Data	Report No.	Remark
Version 1.0	Initial Test Report Release	2017-07-12	CTL1702156501-WF04	Tracy Qi



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1. SUMMARY

1.1. TEST STANDARDS

The tests were performed according to following standards:

FCC Part 22: PRIVATE LAND MOBILE RADIO SERVICES.

TIA/EIA 603 D June 2010: Land Mobile FM or PM Communications Equipment Measurement and Performance Standards.

FCC Part 2: FREQUENCY ALLOCA-TIONS AND RADIO TREATY MAT-TERS; GENERAL RULES AND REG-ULATIONS

KDB971168 D01:v02r02 MEASUREMENT GUIDANCE FOR CERTIFICATION OF LICENSED DIGITAL TRANSMITTERS

ANSI C63.10-2013 Methods of Measurement of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the Range of 9 kHz to 40 GHz

1.2. Test Description

Test Item	Section in CFR 47	Result
RF Output Power	Part 2.1046 Part 22.913(a)	Pass
Peak-to-Average Ratio	N/A	Pass
99% & -26 dB Occupied Bandwidth	Part 2.1049 Part 22.917(b)	Pass
Spurious Emissions at Antenna Terminal	Part 2.1051 Part 22.917(b)	Pass
Field Strength of Spurious Radiation	Part 2.1053 Part 22.917(b)	Pass
Out of band emission, Band Edge	Part 2.1051 Part 22.917(b)	Pass
Frequency stability	Part 2.1055 22.917	Pass

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1.3. Test Facility

1.3.1 Address of the test laboratory

Shenzhen CTL Testing Technology Co., Ltd.

Floor 1-A, Baisha Technology Park, No. 3011, Shahexi Road, Nanshan, Shenzhen 518055 China

There is one 3m semi-anechoic chamber and two line conducted labs for final test. The Test Sites meet the requirements in documents ANSI C63.4 and CISPR 32/EN 55032 requirements.

1.3.2 Laboratory accreditation

The test facility is recognized, certified, or accredited by the following organizations:

IC Registration No.: 9618B

The 3m alternate test site of Shenzhen CTL Testing Technology Co., Ltd. EMC Laboratory has been registered by Certification and Engineer Bureau of Industry Canada for the performance of with Registration No.: 9618B on November 13, 2013.

FCC-Registration No.: 970318

Shenzhen CTL Testing Technology Co., Ltd. EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files. Registration 970318, December 19, 2013.

1.4. Statement of the measurement uncertainty

The data and results referenced in this document are true and accurate. The reader is cautioned that there may be errors within the calibration limits of the equipment and facilities. The measurement uncertainty was calculated for all measurements listed in this test report acc. to CISPR 16 - 4 "Specification for radio disturbance and immunity measuring apparatus and methods — Part 4: Uncertainty in EMC Measurements" and is documented in the Shenzhen CTL Testing Technology Co., Ltd. quality system acc. to DIN EN ISO/IEC 17025. Furthermore, component and process variability of devices similar to that tested may result in additional deviation. The manufacturer has the sole responsibility of continued compliance of the device.

Hereafter the best measurement capability for CTL laboratory is reported:

Test	Range	Measurement Uncertainty	Notes
Radiated Emission	30~1000MHz	4.10dB	(1)
Radiated Emission	Above 1GHz	4.32dB	(1)
Conducted Disturbance	0.15~30MHz	3.20dB	(1)

⁽¹⁾ This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

2. GENERAL INFORMATION

2.1. Environmental conditions

During the measurement the environmental conditions were within the listed ranges:

Normal Temperature:	25°C
Relative Humidity:	55 %
Air Pressure:	101 kPa

2.2. General Description of EUT

Product Name:	8 inch 4G Tablet
Model/Type reference:	TT800Q
Power supply:	DC 3.7V from battery
LTE	
Operation Band:	FDD-LTE: Band 2/4/5/12
Modulation Type:	QPSK, 16QAM
Release Version:	Release 9
Category:	Cat 4
Antenna Type:	PIFA antenna

Note: For more details, refer to the user's manual of the EUT.

2.3. Description of Test Modes

The EUT has been tested under typical operating condition. The CMW500 used to control the EUT staying in continuous transmitting and receiving mode for testing. Regards to the frequency band operation: the lowest middle and highest frequency of channel were selected to perform the test, then shown on this report.

2.4. Equipments Used during the Test

Manufacturer	Model No.	Serial No.	Calibration Date	Calibration Due Date
Sunol Sciences Corp.	esting 7	A061713	2017/06/02	2018/06/01
Sunol Sciences Corp.	JB1	A061714	2017/06/02	2018/06/01
R&S	ESCI	103710	2017/06/02	2018/06/01
Agilent	E4407B	MY41440676	2017/05/21	2018/05/20
Agilent	N9020	US46220290	2017/01/16	2018/01/17
EM Electronics	Controller EM 1000	N/A	2017/05/21	2018/05/20
Sunol Sciences Corp.	DRH-118	A062013	2017/05/19	2018/05/18
Sunol Sciences Corp.	DRH-118	A062014	2017/05/19	2018/05/18
SCHWARZBEC K	FMZB1519	1519-037	2017/05/19	2018/05/18
Agilent	8349B	3008A02306	2017/05/19	2018/05/18
Agilent	8447D	2944A10176	2017/05/19	2018/05/18
	Sunol Sciences Corp. Sunol Sciences Corp. R&S Agilent Agilent EM Electronics Sunol Sciences Corp. Sunol Sciences Corp. SUNOL SCIENCES CORD. SCHWARZBEC K Agilent	Sunol Sciences Corp. Sunol Sciences Corp. R&S ESCI Agilent Agilent N9020 EM Electronics Sunol Sciences Corp. SCHWARZBEC K Agilent 8349B	Sunol Sciences Corp. JB1 A061713 Sunol Sciences Corp. JB1 A061714 R&S ESCI 103710 Agilent E4407B MY41440676 Agilent N9020 US46220290 EM Electronics Controller EM 1000 N/A Sunol Sciences Corp. DRH-118 A062013 Sunol Sciences Corp. DRH-118 A062014 SCHWARZBEC K FMZB1519 1519-037 Agilent 8349B 3008A02306	Manufacturer Model No. Serial No. Date Sunol Sciences Corp. JB1 A061713 2017/06/02 Sunol Sciences Corp. JB1 A061714 2017/06/02 R&S ESCI 103710 2017/06/02 Agilent E4407B MY41440676 2017/05/21 Agilent N9020 US46220290 2017/01/16 EM Electronics Controller EM 1000 N/A 2017/05/21 Sunol Sciences Corp. DRH-118 A062013 2017/05/19 Sunol Sciences Corp. DRH-118 A062014 2017/05/19 SCHWARZBEC K FMZB1519 1519-037 2017/05/19 Agilent 8349B 3008A02306 2017/05/19

Temperature/Humi dity Meter	Gangxing	CTH-608	02	2017/05/20	2018/05/19
Wideband Radio Communication Tester	R&S	CMW500	101814	2016/11/21	2017/11/20
High-Pass Filter	K&L	9SH10-2700/X1 2750-O/O	N/A	2017/05/20	2018/05/19
High-Pass Filter	K&L	41H10-1375/U1 2750-O/O	N/A	2017/05/20	2018/05/19
RF Cable	HUBER+SUHN ER	RG214	N/A	2017/06/02	2018/06/01
Climate Chamber	ESPEC	EL-10KA	A20120523	2017/05/19	2018/05/18
SIGNAL GENERATOR	Agilent	E4421B	US40051744	2017/05/19	2018/05/18
Directional Coupler	Agilent	87300B	3116A03638	2017/05/19	2018/05/18

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2.5. Related Submittal(s) / Grant (s)

This submittal(s) (test report) is intended to comply with of the Part 22 Rules.

2.6. Modifications

No modifications were implemented to meet testing criteria.



3. TEST CONDITIONS AND RESULTS

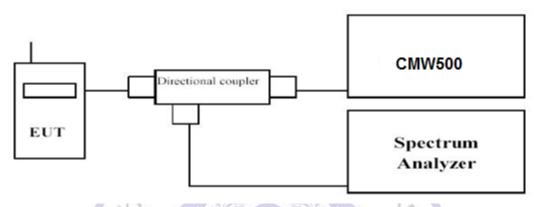
3.1. Output Power

LIMIT

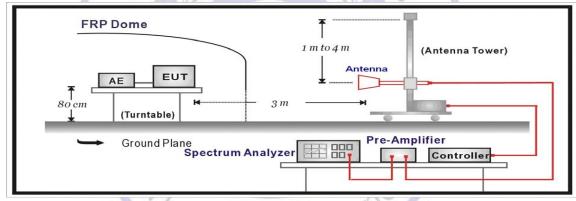
According to § 22.913(a) specifies "The ERP of mobile transmitters and auxiliary test transmitters must not exceed 7 Watts."

TEST CONFIGURATION

Conducted Power Measurement



Radiated Power Measurement:



TEST PROCEDURE

The EUT was setup according to EIA/TIA 603D

Conducted Power Measurement:

- a) Place the EUT on a bench and set it in transmitting mode.
- b) Connect a low loss RF cable from the antenna port to a spectrum analyzer and CMW500 by a Directional Couple.
- c) EUT Communicate with CMW500 then selects a channel for testing.
- d) Add a correction factor to the display of spectrum, and then test.

Radiated Power Measurement:

- a) The EUT shall be placed at the specified height on a support, and in the position closest to normal use as declared by provider.
- b) The test antenna shall be oriented initially for vertical polarization and shall be chosen to correspond to the frequency of the transmitter
- c) The output of the test antenna shall be connected to the measuring receiver.

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d) The transmitter shall be switched on and the measuring receiver shall be tuned to the frequency of the transmitter under test.

- e) The test antenna shall be raised and lowered through the specified range of height until a maximum signal level is detected by the measuring receiver.
- f) The transmitter shall then be rotated through 360° in the horizontal plane, until the maximum signal level is detected by the measuring receiver.
- g) The test antenna shall be raised and lowered again through the specified range of height until a maximum signal level is detected by the measuring receiver.
- h) The maximum signal level detected by the measuring receiver shall be noted.
- i) The transmitter shall be replaced by a substitution antenna.
- j) The substitution antenna shall be orientated for vertical polarization and the length of the substitution antenna shall be adjusted to correspond to the frequency of the transmitter.
- k) The substitution antenna shall be connected to a calibrated signal generator.
- If necessary, the input attenuator setting of the measuring receiver shall be adjusted in order to increase the sensitivity of the measuring receiver.
- m) The test antenna shall be raised and lowered through the specified range of height to ensure that the maximum signal is received.
- n) The input signal to the substitution antenna shall be adjusted to the level that produces a level detected by the measuring receiver, that is equal to the level noted while the transmitter radiated power was measured, corrected for the change of input attenuator setting of the measuring receiver.
- o) The measurement shall be repeated with the test antenna and the substitution antenna orientated for horizontal polarization.
- p) The measure of the effective radiated power is the larger of the two levels recorded at the input to the substitution antenna, corrected for gain of the substitution antenna if necessary.
- q) Test site anechoic chamber refer to ANSI C63.4.

TEST RESULTS

Conducted Measurement:

TX Channel	DD Cina/Officet	Frequency	Average P	ower [dBm]
Bandwidth	RB Size/Offset	(MHz)	QPSK	16QAM
		824.7	21.97	21.20
	1 RB low	836.5	22.85	22.12
		848.3	22.53	22.28
		824.7	22.82	22.62
	1 RB high	836.5	23.05	22.61
1.4 MHz	-	848.3	22.87	22.41
1.4 IVIDZ		824.7	22.95	22.43
	50% RB mid	836.5	23.00	22.58
		848.3	23.00	22.52
		824.7	22.82	22.73
	100% RB	836.5	22.51	21.67
		848.3	22.72	22.43
		825.5	21.64	20.87
	1 RB low	836.5	21.73	20.88
	Kil	847.5	22.23	21.46
		825.5	22.28	21.87
	1 RB high	836.5	21.72	21.08
3 MHz	1.01	847.5	21.68	21.20
3 IVITZ	NX NV	825.5	22.47	21.95
	50% RB mid	836.5	22.27	21.71
		847.5	21.86	21.15
	100% RB	825.5	22.40	21.68
		836.5	21.90	21.24
		847.5	22.79	22.66
		826.5	21.78	20.95
	1 RB low	836.5	22.87	22.28
	2	846.5	22.91	22.50
		826.5	21.81	21.09
	1 RB high	836.5	22.97	22.15
5 MHz	C	846.5	22.06	21.47
2 IVIDZ	//	826.5	21.81	21.09
	50% RB mid	836.5	22.67	21.87
	'esti	846.5	22.88	22.84
		826.5	21.66	21.06
	100% RB	836.5	22.72	22.15
		846.5	22.17	21.36
		829.0	22.72	22.31
	1 RB low	836.5	23.37	21.56
		844.0	23.28	22.90
		829.0	22.12	21.52
	1 RB high	836.5	23.25	21.19
10 MHz		844.0	23.37	20.67
I O IVITIZ		829.0	23.27	21.21
	50% RB mid	836.5	23.29	21.56
		844.0	22.84	22.77
		829.0	21.91	22.52
	100% RB	836.5	22.27	22.11
		844.0	22.57	21.92

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Radiated Measurement:

Remark:

- 1. We were tested all RB Configuration refer 3GPP TS136 521 for each Channel Bandwidth of LTE FDD Band 5; recorded worst case for each Channel Bandwidth of LTE FDD Band 5.
- 2. $EIRP=P_{Mea}(dBm)-P_{cl}(dB)+P_{Ag}(dB)+G_a(dBi)$

LTE FDD Band 5_Channel Bandwidth 1.4MHz_QPSK

Frequency (MHz)	P _{Mea} (dBm)	P _{cl} (dB)	G _a Antenna Gain(dB)	Correction (dB)	P _{Ag} (dB)	ERP (dBm)	Limit (dBm)	Margin (dB)	Polarization
824.7	-19.45	2.42	8.45	2.15	36.82	21.25	38.45	17.20	V
836.5	-18.51	2.46	8.45	2.15	36.82	22.15	38.45	16.30	V
848.3	-19.05	2.53	8.36	2.15	36.82	21.45	38.45	17.00	V

LTE FDD Band 5_Channel Bandwidth 3MHz_QPSK

Frequency (MHz)	P _{Mea} (dBm)	P _{cl} (dB)	G _a Antenna Gain(dB)	Correction (dB)	P _{Ag} (dB)	ERP (dBm)	Limit (dBm)	Margin (dB)	Polarization
825.5	-18.56	2.42	8.45	2.15	36.82	22.14	38.45	16.31	V
836.5	-18.77	2.46	8.45	2.15	36.82	21.89	38.45	16.56	V
847.5	-18.57	2.53	8.36	2.15	36.82	21.93	38.45	16.52	V

LTE FDD Band 5_Channel Bandwidth 5MHz_QPSK

Frequency (MHz)	P _{Mea} (dBm)	P _{cl} (dB)	G _a Antenna Gain(dB)	Correction (dB)	P _{Ag} (dB)	ERP (dBm)	Limit (dBm)	Margin (dB)	Polarization
826.5	-19.04	2.42	8.45	2.15	36.82	21.66	38.45	16.79	V
836.5	-18.88	2.46	8.45	2.15	36.82	21.78	38.45	16.67	V
846.5	-18.78	2.53	8.36	2.15	36.82	21.72	38.45	16.73	V

LTE FDD Band 5_Channel Bandwidth 10MHz_QPSK

ı	Frequency (MHz)	P _{Mea} (dBm)	P _{cl} (dB)	G _a Antenna Gain(dB)	Correction (dB)	P _{Ag} (dB)	ERP (dBm)	Limit (dBm)	Margin (dB)	Polarization
	829.0	-19.05	2.42	8.45	2.15	36.82	21.65	38.45	16.80	V
	836.5	-18.77	2.46	8.45	2.15	36.82	21.89	38.45	16.56	V
	844.0	-18.81	2.53	8.36	2.15	36.82	21.69	38.45	16.76	V

LTE FDD Band 5_Channel Bandwidth 1.4MHz_16QAM

Frequency (MHz)	P _{Mea} (dBm)	P _{cl} (dB)	G _a Antenna Gain(dB)	Correction (dB)	P _{Ag} (dB)	ERP (dBm)	Limit (dBm)	Margin (dB)	Polarization
824.7	-19.83	2.42	8.45	2.15	36.82	20.87	38.45	17.58	V
836.5	-19.88	2.46	8.45	2.15	36.82	20.78	38.45	17.67	V
848.3	-19.87	2.53	8.36	2.15	36.82	20.63	38.45	17.82	V

LTE FDD Band 5_Channel Bandwidth 3MHz_16QAM

Frequency (MHz)	P _{Mea} (dBm)	P _{cl} (dB)	G _a Antenna Gain(dB)	Correction (dB)	P _{Ag} (dB)	ERP (dBm)	Limit (dBm)	Margin (dB)	Polarization
825.5	-20.07	2.42	8.45	2.15	36.82	20.63	38.45	17.82	V
836.5	-19.92	2.46	8.45	2.15	36.82	20.74	38.45	17.71	V
847.5	-19.89	2.53	8.36	2.15	36.82	20.61	38.45	17.84	V

LTE FDD Band 5_Channel Bandwidth 5MHz_16QAM

Frequency (MHz)	P _{Mea} (dBm)	P _{cl} (dB)	G _a Antenna Gain(dB)	Correction (dB)	P _{Ag} (dB)	ERP (dBm)	Limit (dBm)	Margin (dB)	Polarization
826.5	-20.15	2.42	8.45	2.15	36.82	20.55	38.45	17.90	V
836.5	-20.08	2.46	8.45	2.15	36.82	20.58	38.45	17.87	V
846.5	-19.77	2.53	8.36	2.15	36.82	20.73	38.45	17.72	V

LTE FDD Band 5_Channel Bandwidth 10MHz_16QAM

Frequency (MHz)	P _{Mea} (dBm)	P _{cl} (dB)	G _a Antenna Gain(dB)	Correction (dB)	P _{Ag} (dB)	ERP (dBm)	Limit (dBm)	Margin (dB)	Polarization
829.0	-19.85	2.42	8.45	2.15	36.82	20.85	38.45	17.60	V
836.5	-20.00	2.46	8.45	2.15	36.82	20.66	38.45	17.79	V
844.0	-19.69	2.53	8.36	2.15	36.82	20.81	38.45	17.64	V

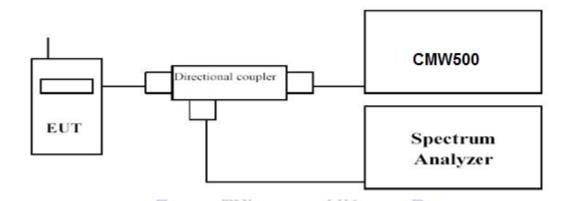


3.2. Peak-to-Average Ratio (PAR)

LIMIT

The Peak-to-Average Ratio (PAR) of the transmission may not exceed 13 dB.

TEST CONFIGURATION



TEST PROCEDURE

- Refer to instrument's analyzer instruction manual for details on how to use the power statistics/CCDF function;
- 2. Set resolution/measurement bandwidth ≥ signal's occupied bandwidth;
- 3. Set the number of counts to a value that stabilizes the measured CCDF curve;
- 4. Set the measurement interval as follows:
 - 1). for continuous transmissions, set to 1 ms,
 - 2). for burst transmissions, employ an external trigger that is synchronized with the EUT burst timing sequence, or use the internal burst trigger with a trigger level that allows the burst to stabilize and set the measurement interval to a time that is less than or equal to the burst duration.

Testing Tech

5. Record the maximum PAPR level associated with a probability of 0.1%.

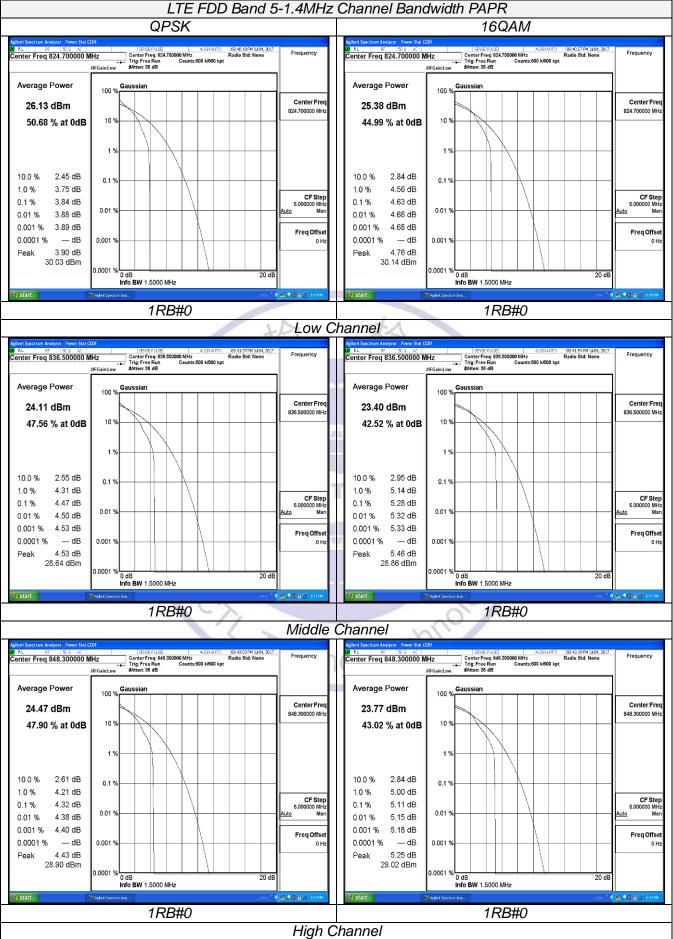
TEST RESULTS

Remark:

1. We were tested all RB Configuration refer 3GPP TS136 521 for each Channel Bandwidth of LTE FDD Band 5; recorded worst case for each Channel Bandwidth of LTE FDD Band 5.

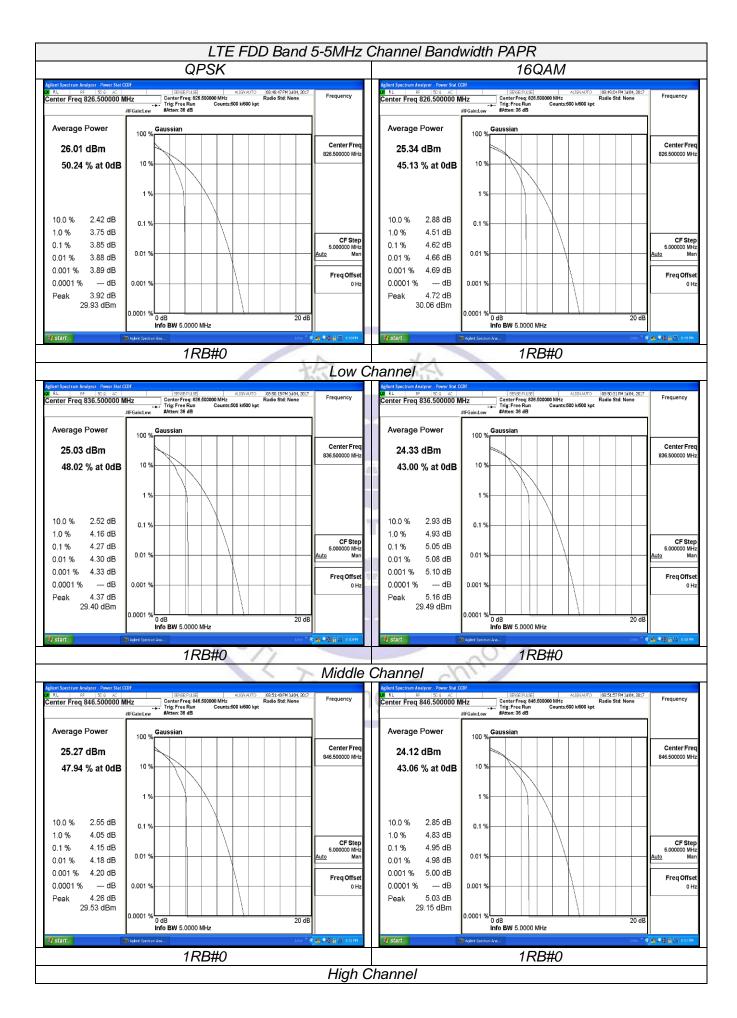
	LTE FDD Band 5										
TX Channel	Frequency	RB Size/Offset	PAPR (dB)								
Bandwidth	(MHz)	NB Size/Offset	QPSK	16QAM							
	824.7		3.84	4.63							
1.4 MHz	836.5	1RB#0	4.47	5.28							
	848.3		4.32	5.11							
	825.5		3.85	4.49							
3 MHz	836.5	1RB#0	4.42	5.18							
	847.5		4.17	4.97							
	826.5		3.85	4.62							
5 MHz	836.5	1RB#0	4.27	5.05							
	846.5		4.15	4.95							
	829.0		3.87	4.61							
10 MHz	836.5	1RB#0	4.34	5.12							
	844.0	. 1 40	4.46	5.24							





High Channel

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0 dB Info BW 8.0000 MHz

1RB#0

High Channel

1RB#0

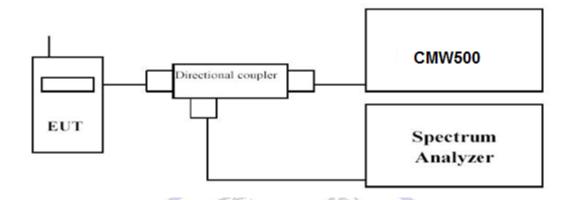
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3.3. Occupied Bandwidth and Emission Bandwidth

LIMIT

N/A

TEST CONFIGURATION



TEST PROCEDURE

The transmitter output was connected to a calibrated coaxial cable and coupler, the other end of which was connected to a spectrum analyzer. The occupied bandwidth was measured with the spectrum analyzer at low, middle and high channel in each band. The -26dBc Emission bandwidth was also measured and recorded.

Set RBW was set to about 1% of emission BW, VBW≥3 times RBW.

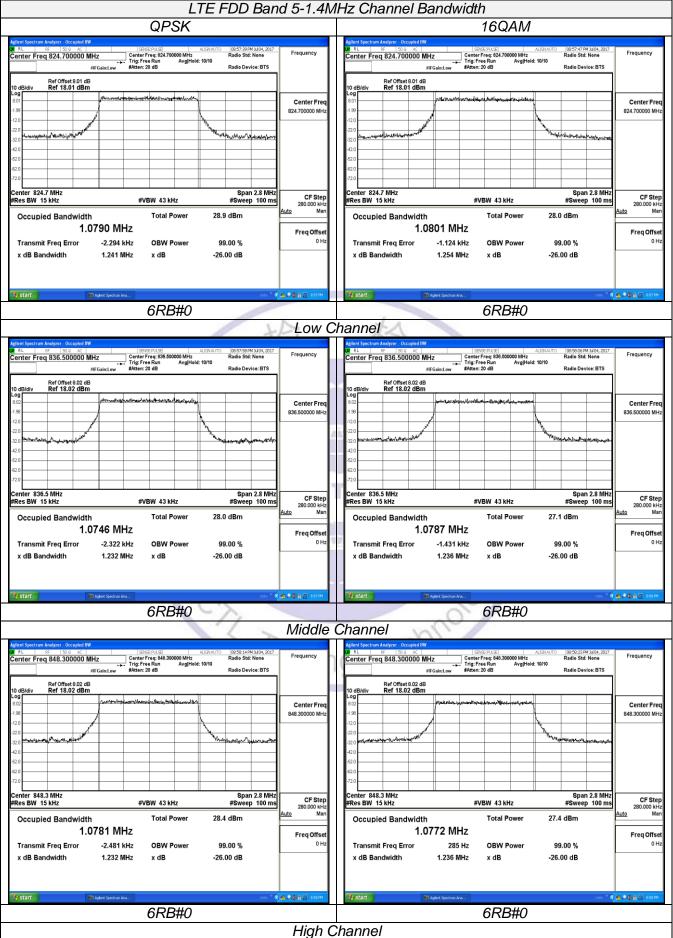
-26dBc display line was placed on the screen (or 99% bandwidth), the occupied bandwidth is the delta frequency between the two points where the display line intersects the signal trace.

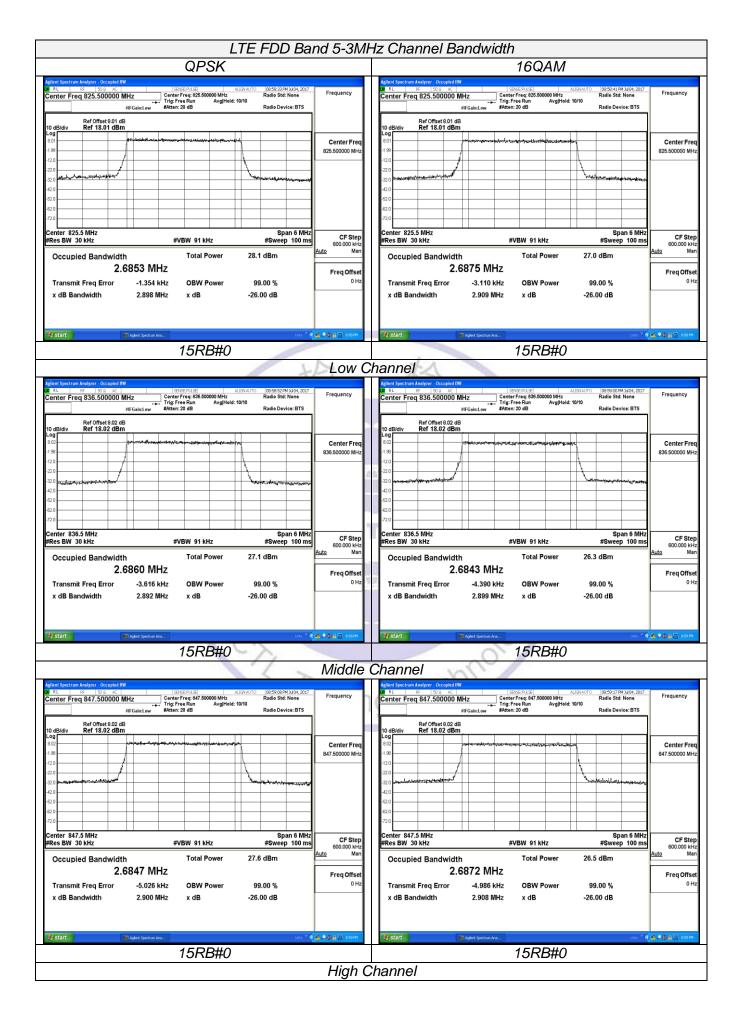
TEST RESULTS

Remark:

1. We were tested all RB Configuration refer 3GPP TS136 521 for each Channel Bandwidth of LTE FDD Band 5; recorded worst case for each Channel Bandwidth of LTE FDD Band 5.

		LTE FDD	Band 5			
TX		Fraguenay	-26dBc I	Emission	99% O	ccupied
Channel	RB Size/Offset	Frequency	bandwid	th (MHz)	bandwid	th (MHz)
Bandwidth		(MHz)	QPSK	16QAM	QPSK	16QAM
		824.7	1.241	1.254	1.0790	1.0801
1.4 MHz	6RB#0	836.5	1.232	1.236	1.0746	1.0787
		848.3	1.232	1.236	1.0781	1.0772
		825.5	2.898	2.909	2.6853	2.6875
3 MHz	15RB#0	836.5	2.892	2.899	2.6860	2.6843
		847.5	2.900	2.908	2.6847	2.6872
		826.5	4.801	4.814	4.4778	4.4741
5 MHz	25RB#0	836.5	4.831	4.821	4.4784	4.8370
		846.5	4.789	4.814	4.4746	4.4790
		829.0	9.478	9.461	8.9393	8.9330
10 MHz	50RB#0	836.5	9.494	9.399	8.9440	8.9346
		844.0	9.408	9.386	8.9001	8.9238





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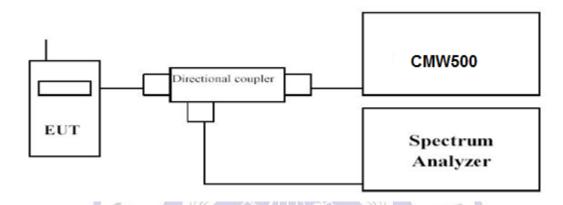
3.4. Band Edge compliance

LIMIT

According to Part §22.917 specify that the power of any emission outside of the authorized operating frequency ranges must be attenuated below the transmitting power (P) by a factor of at least 43 + 10 log (P) dB.

The specification that emissions shall be attenuated below the transmitter power (P) by at least 43 + 10 log (P) dB, translates in the relevant power range (1 to 0.001 W) to -13 dBm. At 1 W the specified minimum attenuation becomes 43 dB and relative to a 30 dBm (1 W) carrier becomes a limit of -13 dBm. At 0.001 W (0 dBm) the minimum attenuation is 13 dB, which again yields a limit of -13 dBm. In this way a translation of the specification from relative to absolute terms is carried out.

TEST CONFIGURATION



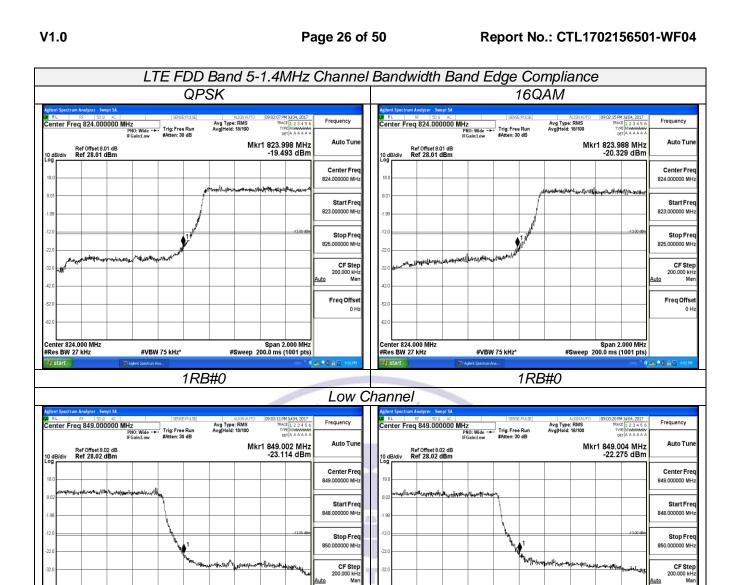
TEST PROCEDURE

- 1. The transmitter output port was connected to base station.
- 2. The RF output of EUT was connected to the power meter by RF cable and attenuator, the path loss was compensated to the results for each measurement.
- 3. Set EUT at maximum power through base station.
- 4. Select lowest and highest channels for each band and different modulation.
- 5. Measure Band edge using RMS (Average) detector by spectrum

TEST RESULTS

Remark:

 We were tested all RB Configuration refer 3GPP TS136 521 for each Channel Bandwidth of LTE FDD Band 5; recorded worst case for each Channel Bandwidth of LTE FDD Band 5.



Freq Offse

High Channel

Span 2.000 MHz #Sweep 200.0 ms (1001 pts)

Center 849.000 MHz #Res BW 27 kHz

#VBW 75 kHz*

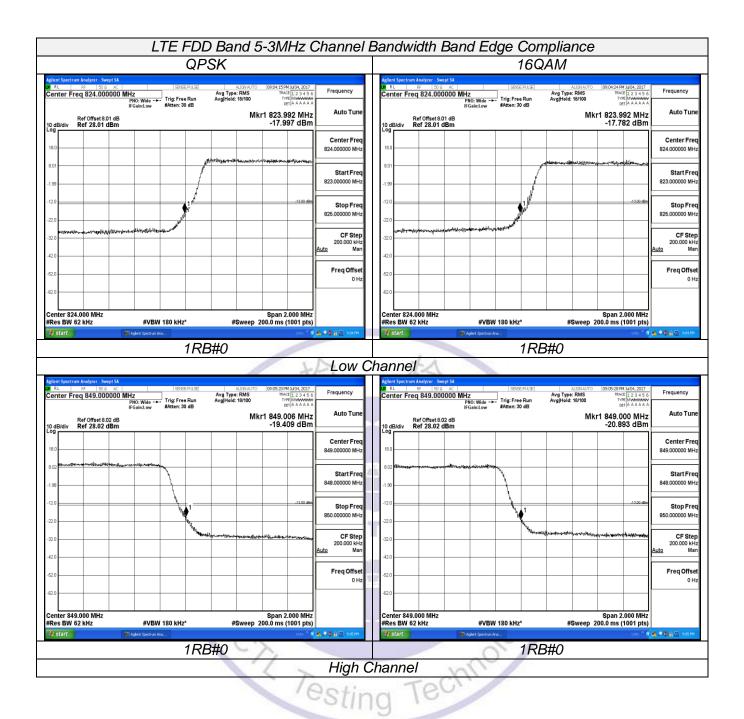
1RB#0

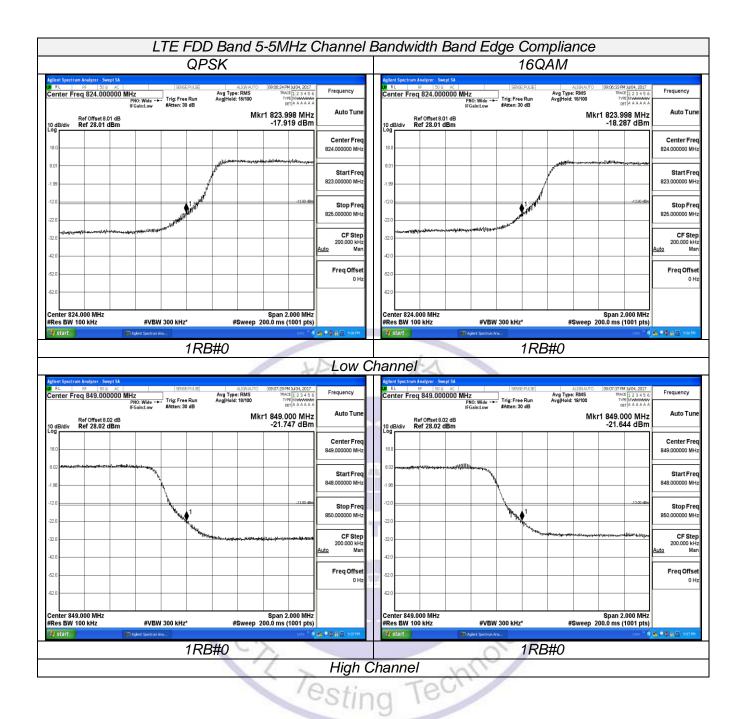
Freq Offse

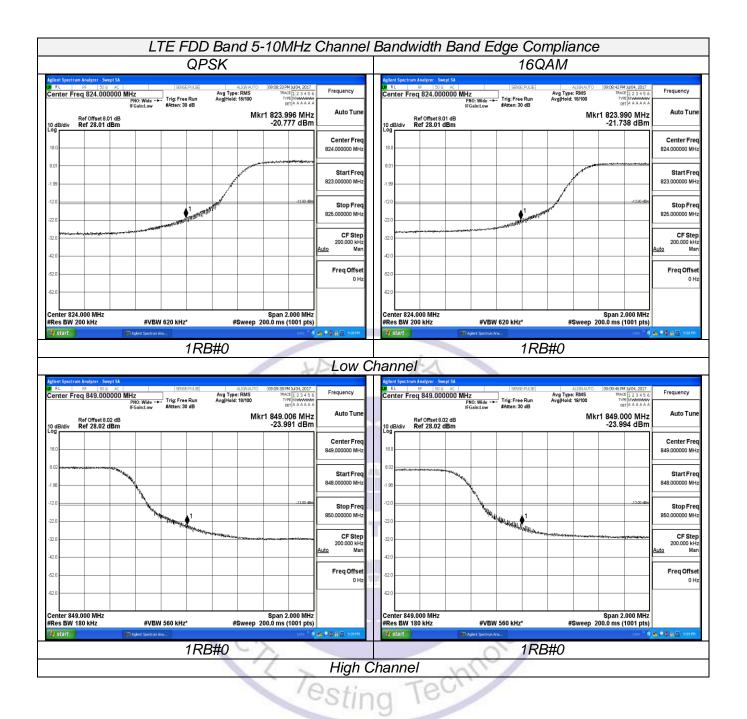
Span 2.000 MHz #Sweep 200.0 ms (1001 pts)

#VBW 75 kHz*

1RB#0







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3.5. Spurious Emission

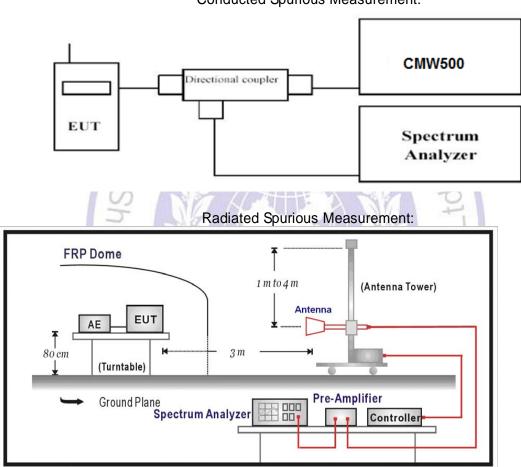
LIMIT

According to Part §22.917 specify that the power of any emission outside of the authorized operating frequency ranges must be attenuated below the transmitting power (P) by a factor of at least 43 + 10 log (P) dB.

The specification that emissions shall be attenuated below the transmitter power (P) by at least 43 + 10 log (P) dB, translates in the relevant power range (1 to 0.001 W) to -13 dBm. At 1 W the specified minimum attenuation becomes 43 dB and relative to a 30 dBm (1 W) carrier becomes a limit of -13 dBm. At 0.001 W (0 dBm) the minimum attenuation is 13 dB, which again yields a limit of -13 dBm. In this way a translation of the specification from relative to absolute terms is carried out.

TEST CONFIGURATION

Conducted Spurious Measurement:



TEST PROCEDURE

The EUT was setup according to EIA/TIA 603D

Conducted Spurious Measurement:

- a. Place the EUT on a bench and set it in transmitting mode.
- b. Connect a low loss RF cable from the antenna port to a spectrum analyzer and CMW500 by a Directional Couple.
- c. EUT Communicate with CMW500 then selects a channel for testing.
- d. Add a correction factor to the display of spectrum, and then test.
- e. The resolution bandwidth of the spectrum analyzer was set sufficient scans were taken to show the out of band Emission if any up to 10th harmonic.